

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination HE ET AL.	
		Examiner Shick C Hom	Art Unit 2666	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0141505	10-2002	Lundby, Stein A.	375/261
	B	US-2002/0119796	08-2002	Vanghi, Vieri	455/522
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 1089456 A2	09-2000	European	Wang	H04B 7/005
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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